

PBHV8115Z

150 V, 1 A NPN high-voltage low V_{CEsat} (BISS) transistor

Rev. 01 — 5 February 2008 Product data

Product data sheet

1. Product profile

1.1 General description

NPN high-voltage low V_{CEsat} Breakthrough In Small Signal (BISS) transistor in a SOT223 (SC-73) medium power Surface-Mounted Device (SMD) plastic package.

PNP complement: PBHV9115Z.

1.2 Features

- High voltage
- Low collector-emitter saturation voltage V_{CEsat}
- High collector current capability I_C and I_{CM}
- High collector current gain (h_{FE}) at high I_C
- AEC-Q101 qualified

1.3 Applications

- LED driver for LED chain module
- LCD backlighting
- High Intensity Discharge (HID) front lighting
- Automotive motor management
- Hook switch for wired telecom
- Switch mode power supply

1.4 Quick reference data

Table 1. **Quick reference data**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{CEO}	collector-emitter voltage	open base	-	-	150	V
I_{C}	collector current		-	-	1	Α
h _{FE}	DC current gain	$V_{CE} = 10 \text{ V}; I_{C} = 50 \text{ mA}$	100	-	-	



150 V, 1 A NPN high-voltage low V_{CEsat} (BISS) transistor

2. Pinning information

Table 2. Pinning

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Pin	Description	Simplified outline	Symbol
1	base		
2	collector	4	2, 4
3	emitter		1—
4	collector		. ,
			3
			sym016

3. Ordering information

Table 3. Ordering information

Type number	Package	ackage				
	Name	Description	Version			
PBHV8115Z	SC-73	plastic surface-mounted package with increased heatsink; 4 leads	SOT223			

4. Marking

Table 4. Marking codes

Type number	Marking code
PBHV8115Z	V8115Z

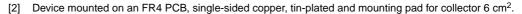
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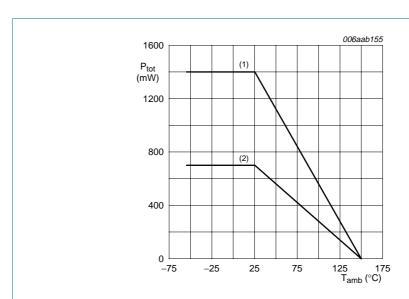
5. Limiting values

Table 5. Limiting values
In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{CBO}	collector-base voltage	open emitter	-	400	V
V_{CEO}	collector-emitter voltage	open base	-	150	V
V_{EBO}	emitter-base voltage	open collector	-	6	V
I _C	collector current		-	1	Α
I _{CM}	peak collector current	single pulse; $t_p \le 1 \text{ ms}$	-	2	Α
I _{BM}	peak base current	single pulse; $t_p \le 1 \text{ ms}$	-	100	mA
P _{tot}	total power dissipation	$T_{amb} \le 25 ^{\circ}C$	<u>[1]</u> _	0.7	W
			[2] _	1.4	W
Tj	junction temperature		-	150	°C
T_{amb}	ambient temperature		-55	+150	°C
T_{stg}	storage temperature		-65	+150	°C

^[1] Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.





- (1) FR4 PCB, mounting pad for collector 6 cm²
- (2) FR4 PCB, standard footprint

Fig 1. Power derating curves

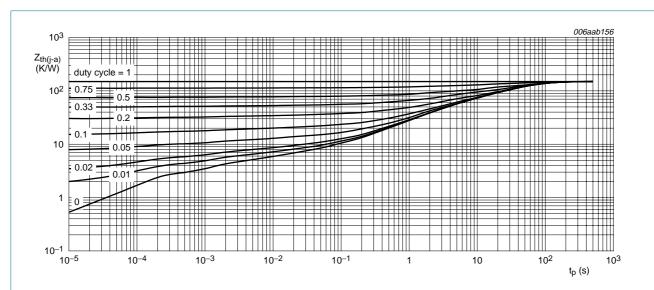
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6. Thermal characteristics

Table 6. Thermal characteristics

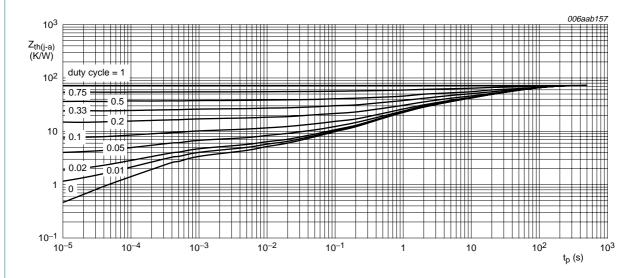
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	[1]	-	175	K/W
			[2]	-	89	K/W
$R_{th(j-sp)}$	thermal resistance from junction to solder point		-	-	20	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated and mounting pad for collector 6 cm².



FR4 PCB, standard footprint

Fig 2. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for collector 6 cm²

Fig 3. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

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7. Characteristics

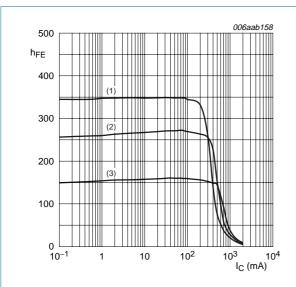
Table 7. Characteristics

 $T_{amb} = 25 \,^{\circ}C$ unless otherwise specified.

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Symbol	Parameter	Conditions		Min	Тур	Max	Unit
I_{CBO}		$V_{CB} = 120 \text{ V}; I_E = 0 \text{ A}$		-	-	100	nA
	current	$V_{CB} = 120 \text{ V}; I_E = 0 \text{ A};$ $T_j = 150 \text{ °C}$		-	-	10	μΑ
I _{CES}	collector-emitter cut-off current	$V_{CE} = 120 \text{ V}; V_{BE} = 0 \text{ V}$		-	-	100	nA
I _{EBO}	emitter-base cut-off current	$V_{EB} = 4 \text{ V}; I_C = 0 \text{ A}$		-	-	100	nA
h _{FE}	DC current gain	V _{CE} = 10 V					
		$I_C = 50 \text{ mA}$		100	250	-	
		I _C = 100 mA		100	250	-	
		$I_C = 0.5 A$	<u>[1]</u>	50	160	-	
		I _C = 1 A	[1]	10	30	-	
V _{CEsat}	collector-emitter saturation voltage	$I_C = 100 \text{ mA}; I_B = 10 \text{ mA}$		-	40	60	mV
		I _C = 100 mA; I _B = 20 mA		-	33	50	mV
		I _C = 1 A; I _B = 200 mA	<u>[1]</u>	-	225	350	mV
V_{BEsat}	base-emitter saturation voltage	$I_C = 1 A; I_B = 200 \text{ mA}$	[1]	-	1.1	1.2	V
f _T	transition frequency	$V_{CE} = 10 \text{ V}; I_{E} = 10 \text{ mA};$ f = 100 MHz		-	30	-	MHz
C _c	collector capacitance	V_{CB} = 20 V; I_E = i_e = 0 A; f = 1 MHz		-	5.7	-	pF
C _e	emitter capacitance	$V_{EB} = 0.5 \text{ V};$ $I_C = i_c = 0 \text{ A}; f = 1 \text{ MHz}$		-	150	-	pF
t _d	delay time	$V_{CC} = 6 \text{ V}; I_C = 0.5 \text{ A};$		-	7	-	ns
t _r	rise time	$I_{Bon} = 0.1 \text{ A};$		-	565	-	ns
t _{on}	turn-on time	- I _{Boff} = −0.1 A -		-	572	-	ns
t _s	storage time			-	1530	-	ns
t _f	fall time			-	700	-	ns
t _{off}	turn-off time			-	2230	-	ns

^[1] Pulse test: $t_p \le 300 \ \mu s; \ \delta \le 0.02.$

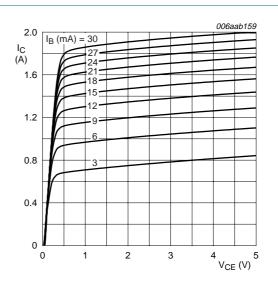
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$$V_{CE} = 10 \text{ V}$$

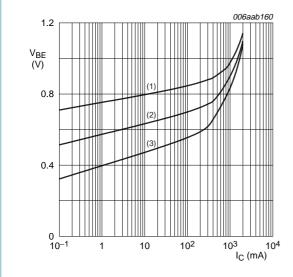
- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) $T_{amb} = 25 \,^{\circ}C$
- (3) $T_{amb} = -55 \, ^{\circ}C$

Fig 4. DC current gain as a function of collector current; typical values



 $T_{amb} = 25 \, ^{\circ}C$

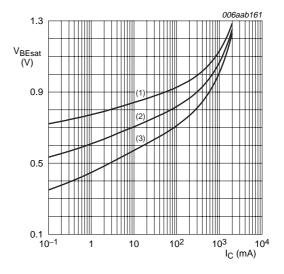
Fig 5. Collector current as a function of collector-emitter voltage; typical values





- (1) $T_{amb} = -55 \,^{\circ}C$
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = 100 \, ^{\circ}C$

Fig 6. Base-emitter voltage as a function of collector current; typical values

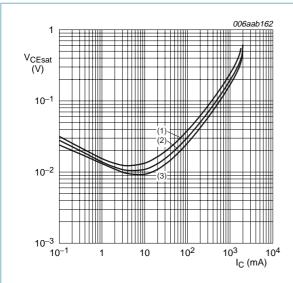


 $I_{\rm C}/I_{\rm B}=5$

- (1) $T_{amb} = -55$ °C
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = 100 \, ^{\circ}C$

Fig 7. Base-emitter saturation voltage as a function of collector current; typical values

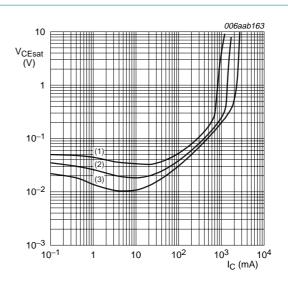
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$$I_{\rm C}/I_{\rm B}=5$$

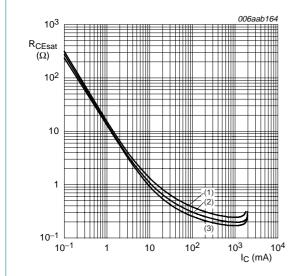
- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = -55 \, ^{\circ}C$

Fig 8. Collector-emitter saturation voltage as a function of collector current; typical values



- (1) $I_C/I_B = 20$
- (2) $I_C/I_B = 10$
- (3) $I_C/I_B = 5$

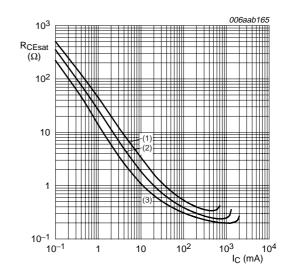
Fig 9. Collector-emitter saturation voltage as a function of collector current; typical values





- (1) $T_{amb} = 100 \, ^{\circ}C$
- (2) $T_{amb} = 25 \, ^{\circ}C$
- (3) $T_{amb} = -55 \, ^{\circ}C$

Fig 10. Collector-emitter saturation resistance as a function of collector current; typical values

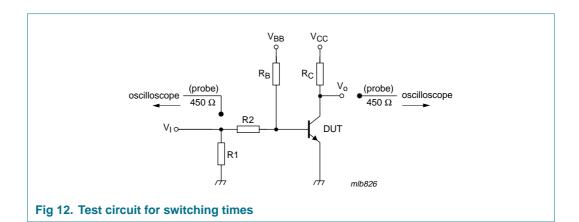


- (1) $I_C/I_B = 20$
- (2) $I_C/I_B = 10$
- (3) $I_C/I_B = 5$

Fig 11. Collector-emitter saturation resistance as a function of collector current; typical values

150 V, 1 A NPN high-voltage low V_{CEsat} (BISS) transistor

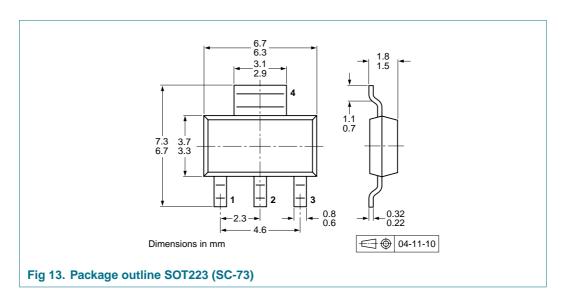
8. Test information



8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

9. Package outline



10. Packing information

Table 8. Packing methods

The indicated -xxx are the last three digits of the 12NC ordering code.[1]

Type number	umber Package Description P		Packing (quantity
			1000	4000
PBHV8115Z	SOT223	8 mm pitch, 12 mm tape and reel	-115	-135

^[1] For further information and the availability of packing methods, see Section 14.

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11. Soldering

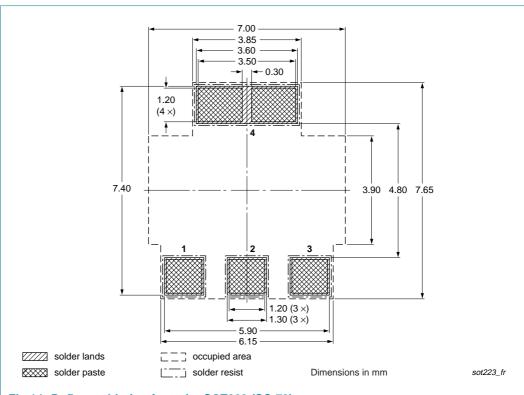
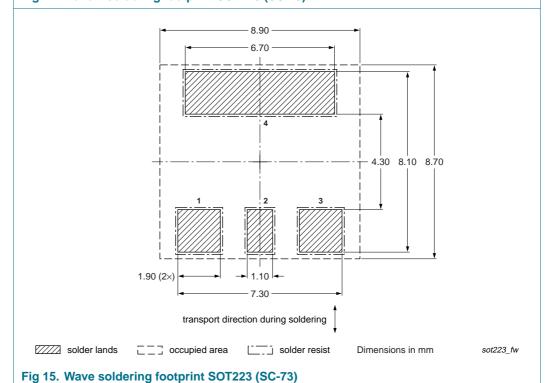


Fig 14. Reflow soldering footprint SOT223 (SC-73)



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12. Revision history

Table 9. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PBHV8115Z_1	20080205	Product data sheet	-	-

150 V, 1 A NPN high-voltage low V_{CEsat} (BISS) transistor

13. Legal information

13.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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15. Contents

1	Product profile
1.1	General description
1.2	Features
1.3	Applications
1.4	Quick reference data
2	Pinning information 2
3	Ordering information
4	Marking 2
5	Limiting values 3
6	Thermal characteristics 4
7	Characteristics 5
8	Test information 8
8.1	Quality information 8
9	Package outline 8
10	Packing information 8
11	Soldering 9
12	Revision history
13	Legal information
13.1	Data sheet status
13.2	Definitions
13.3	Disclaimers
13.4	Trademarks11
14	Contact information 11
15	Contents

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